

Search Notes**Application/Control No.**

10/635,916

Examiner

Hien X. Vo

Applicant(s)/Patent under Reexamination

SWAINE ET AL.

Art Unit

2863

SEARCHED

Class	Subclass	Date	Examiner
702	176	4/15/2005	VXH
	177		
	178		
	187		
711	162		
	154		
717	124		
	128		
714	45		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLus search	3/9/2005	VXH
EAST	4/13/2005	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner